

Search Notes



Application/Control No.

09/955,146

Examiner

Ashutosh Upreti

Applicant(s)/Patent under Reexamination

TERASAKI, HIROSHI

Art Unit

2623

SEARCHED

Class	Subclass	Date	Examiner
382	100, 298, 299, 240, 302, 305, 232	09/29/04	A.U.
709	203	9/29/04	A.U.
705	57	9/29/04	A.U.
713	176	9/29/04	A.U.
updated search		04/21/05	A.U.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
382	298, 240, 302, 305, 232	04/21/05	AU
709	203	04/21/05	AU
705	57	04/21/05	AU
713	176	04/21/05	AU

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Talked to Jon Chang: Search: 382/100, 298, 299 + IEEE (NPL)	9/29/04	A.U.
Talked to Andy Johns: Search: 382/100, 232 709, 713/176 705	9/29/04	A.U.
Talked to Wenpeng Chen Search: 382/240, 302, 305 709	9/29/04	A.U.
STIC searched NPL for watermark in low res- olution part of high resolution image	10/26/04	A.U.
STIC searched for: output of high resolution data if watermark detected, else output of low resolution data	11/03/04	A.U.
Conducted search in EAST-see search history (including EPO, JPO, Derwent)	11/22/04	A.U.
Searched IEEE Xplore for "watermark (and) resolution"	11/22/04	A.U.